



Dr. Devin Giddings

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Dr. A. D. Giddings (Devin) is Technical Sales Director at Infinitesima Limited, where he leads the integration of ultra-fast atomic force microscopy (AFM) systems for 3D metrology and inspection in high-volume semiconductor manufacturing. With over two decades of experience in semiconductor nano-characterization, Devin has been at the forefront of nanoscale analysis across a wide-range of devices, including Si logic, DRAM, NAND, GaN and GaAs based materials.

His career spans key roles at leading industry players such as TSMC, where he served as Technical Manager and establishing a cutting-edge characterization lab, and Toshiba, where – as Toshiba Fellow – he conducted research into novel spintronic materials. He was also a Visiting Scholar at NIMS, where here was responsible for a facility developing industrial applications for advanced 3D microscopy.

Devin holds a bachelor's degree in mathematics & physics from the University of Warwick, a doctorate in semiconductor spintronics from the University of Nottingham, and a master's degree in law from the University of Law. He is a member of the Institute of Physics (IOP) and a Fellow of the Royal Society of Arts, Manufactures and Commerce (RSA).